


<b>Search Notes</b> 	<b>Application/Control No.</b> 10042231	<b>Applicant(s)/Patent Under Reexamination</b> NAKANO, MASAKI
	<b>Examiner</b> AARON M RICHER	<b>Art Unit</b> 2628

SEARCHED			
Class	Subclass	Date	Examiner
345	588 - updated	4/15/08	AMR
Above	Updated	12/3/08	AMR

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (US-PGPUB; USPAT; EPO; JPO; DERWENT, IBM_TDB) - see search history printout	4/15/08	AMR
Updated	12/3/08	AMR

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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